

Search Notes

Application/Control No.

10/577,235

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

HAYASHI ET AL.

Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
427	251	9/17/2008	BT
427	569	9/17/2008	BT
427	583	9/17/2008	BT
427	584	9/17/2008	BT
118	720	9/17/2008	BT
118	723R	9/17/2008	BT
118	730	9/17/2008	BT

INTERFERENCE SEARCHED

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427	251	9/17/2008	BT
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427	583	9/17/2008	BT
427/584 118/720 118/723R 118/730		9/17/2008	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using databases in EAST	9/17/2008	BT